

Title (en)

X-RAY REFLECTIVITY APPARATUS AND METHOD

Title (de)

RÖNTGENSTRAHLUNGSREFLEKTIONSAPPARATUR UND VERFAHREN

Title (fr)

APPAREIL ET PROCÉDÉ À RÉFLECTIVITÉ DES RAYONS X

Publication

**EP 1311835 A2 20030521 (EN)**

Application

**EP 01934187 A 20010601**

Priority

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Abstract (en)

[origin: WO0196841A2] A method and corresponding apparatus for determining one or more physical parameters, such as electron density, of a target surface of a sample are disclosed. The target surface is irradiated with X-rays of at least two different wavelengths over a range of angles of incidence, and the physical parameter is determined by combining measurements of the intensity of these X-rays following specular reflection. The X-rays at two different wavelengths may be simultaneously generated using a metal alloy anode.

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